

Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D
Characterisation and Imaging with Ion Beams | (smr 2856)

Contribution ID : 21

Type : **not specified**

Comparison of External Ion Imaging Techniques with Alternative Techniques

Thursday, 29 September 2016 15:30 (1:00)

Content

With laboratory-based chemical imaging techniques (e.g. X-ray radiography, SEM-EDX, Raman, MA-XRF) With large scale facility (e.g. Synchrotron, Neutron sources) Synchrotron Neutron source external IBA XRF NAA PIXE, PIGE XAS n-Radiography RBS, NRA XRD n-Diffraction IBIL Emerging techniques Full field XRF MeV-TOF SIMS

Summary

Presenter(s) : CALLIGARO, Thomas (C2RMF - AGLAE Laboratory, Paris, France)

Session Classification : DAY 4